

Search Notes

Application/Control No.

10/528,120

Examiner

JOHN J. LEE

Applicant(s)/Patent under
Reexamination

NISHIO ET AL.

Art Unit

2618

SEARCHED

Class	Subclass	Date	Examiner
455	522,69 515,450 509,13.4 517	1/14/2009	J.L
455	452.1	1/14/2009	J.L
455	67.11	1/14/2009	J.L

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
455	522,69	1/16/2009	J.L
455	452.1,517	1/16/2009	J.L
455	509,13.4	1/16/2009	J.L
Interference and Inventor search		1/16/2009	J.L

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	1/14/2009	J.L